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SP2: First measurements for integrated spectrometer with multiple spectral points at TELBE

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Semiconductor based detectors can be used at room temperature and provide bandwidths that are high enough for phase-sensitive detection at the repetition rate of the accelerator. Such an integrated spectrometer may replace the classical single element semiconductor detectors. A demonstrator with multiple spectral points produced in the BMBF funded project "InSEI" has been successfully tested at TELBE. First measurement results are presented and an outlook to the follow-up project "SAMoS" is given.

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